FAIRCHILD SEMICONDUCTOR®

FDS6670S 30V N-Channel PowerTrench^o SyncFET[™]

General Description

The FDS6670S is designed to replace a single SO-8 MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{DS(ON)}$ and low gate charge. The FDS6670S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

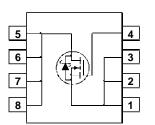
Applications

- DC/DC converter
- Motor drives



Features

- 13.5 A, 30 V. $R_{DS(ON)} = 9 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 12.5 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- Includes SyncFET Schottky body diode
- Low gate charge (24nC typical)
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$ and fast switching
- High power and current handling capability



Absolute Maximum Ratings T_A=25°C unless otherwise noted

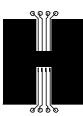
Symbol	Parameter			Ratings		
V _{DSS}	Drain-Sourc	ce Voltage		30	V	
V _{GSS}	Gate-Sourc	ource Voltage		±20	V	
I _D	Drain Current – Continuous (Note 1a)		(Note 1a)	13.5		
	– Pulsed			50		
P _D	Power Diss	ipation for Single Operat	ion (Note 1a)	2.5	W	
			(Note 1b)	1.2		
			(Note 1c)	1		
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150		
Therma	I Charac	teristics esistance, Junction-to-Am	nbient (Note 1a)	50	°C/W	
R _{ejc}	Thermal Resistance, Junction-to-Case (Note 1)			25 °(
Packaq		g and Ordering				
	Marking	Device	Reel Size	Tape width	Quantity	
Device	ananng					

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 1 mA$	30			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		24		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			500	μΑ
GSSF	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
GSSR	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	1	2.2	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		-6.2		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance			7 9.5 9	9 12.5 12.5	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	50			Α
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 13.5 \text{ A}$		45		S
Dynamic	Characteristics	-				
C _{iss}	Input Capacitance	$V_{DS} = 15 V$, $V_{GS} = 0 V$,		2674		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		751		pF
C _{rss}	Reverse Transfer Capacitance			254		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time	$V_{\text{DS}} = 15 \text{ V}, \qquad I_{\text{D}} = 1 \text{ A},$		11	20	ns
t _r	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	20	ns
t _d (_{off})	Turn-Off Delay Time			44	70	ns
t _f	Turn–Off Fall Time			23	37	ns
Q _g	Total Gate Charge	$V_{DS} = 15 V$, $I_{D} = 13.5 A$,		24	34	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		7.3		nC
Q _{gd}	Gate-Drain Charge			6		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings				
I _S	Maximum Continuous Drain-Source	-			3.5	Α
V _{SD}	Drain–Source Diode Forward Voltage	$ \begin{array}{c c} V_{GS} = 0 \ V, & I_S = 3.5 \ A & (Note \ 2) \\ V_{GS} = 0 \ V, & I_S = 7 \ A & (Note \ 2) \end{array} $		0.4 0.5	0.7	V
t _{rr}	Diode Reverse Recovery Time	I _F = 13.5A,		26.8		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A}/\mu \text{s}$ (Note 3)		47.2		nC



a) 50°C/W when mounted on a 1 in² pad of 2 oz copper



 φ φ φ φ
b) 105°C/W when mounted on a .04 in² pad of 2 oz copper

c) 125°C/W when mounted on a minimum pad.

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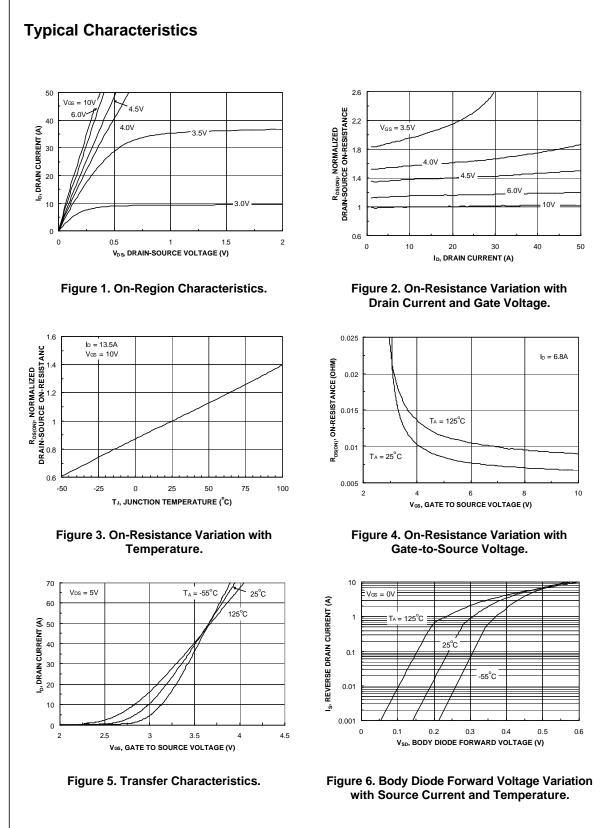
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Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

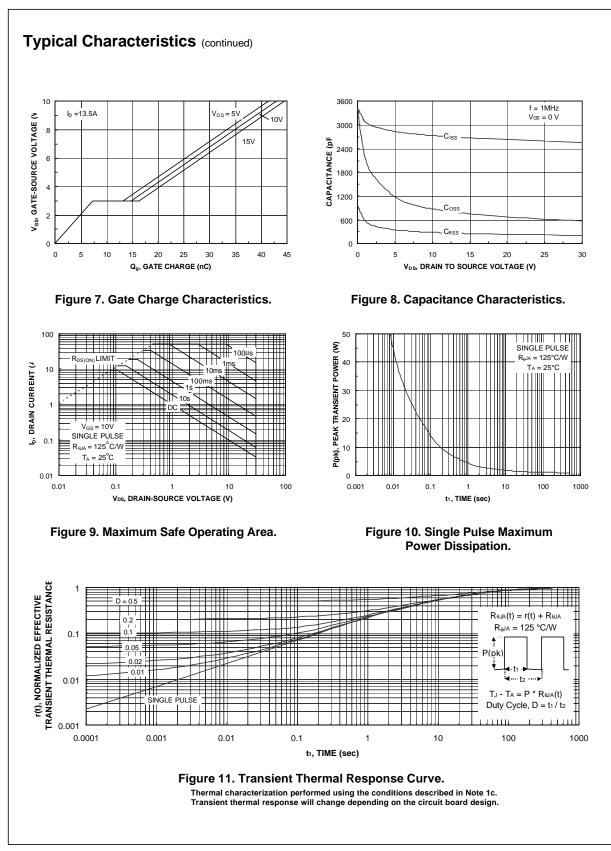
3. See "SyncFET Schottky body diode characteristics" below.

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Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS6670S.

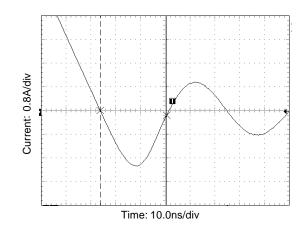
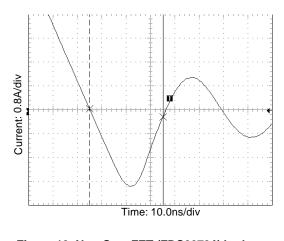


Figure 12. FDS6670S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6670A).





Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

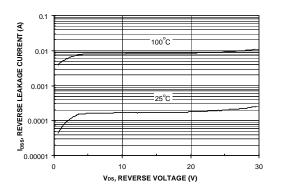


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

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